83940-01

Low Skew, 1-to-18 LVPECL-TO-LVCMOS / LVTTL Fanout Buffer

DATASHEET

GENERAL DESCRIPTION

The ICS83940-01 is a low skew, 1-to-18 LVPECL-to-LVCMOS/LVTTL Fanout Buffer. The ICS83940-01 has two selectable clock inputs. The PCLK, nPCLK pair can accept LVPECL, CML or SSTL input levels. The single ended clock input accepts LVCMOS or LVTTL input levels. The low impedance LVCMOS/LVTTL outputs are designed to drive 50Ω series or parallel terminated transmission lines. The effective fanout can be increased from 18 to 36 by utilizing the ability of the outputs to drive two series terminated lines.

The ICS83940-01 is characterized at full 3.3V, full 2.5V and mixed 3.3V input and 2.5V output operating supply modes. Guaranteed output and part-to-part skew characteristics make the ICS83940-01 ideal for those clock distribution applications demanding well defined performance and repeatability.

FEATURES

- Eighteen LVCMOS/LVTTL outputs, 23Ω typical output impedance
- Selectable LVCMOS_CLK or LVPECL clock inputs
- LVCMOS_CLK supports the following input types: LVCMOS or LVTTL
- PCLK, nPCLK supports the following input types: LVPECL, CML, SSTL
- Maximum output frequency: 250MHz
- Output skew: 85ps (maximum)
- Part-to-part skew: 750ps (maximum)
- Full 3.3V, 2.5V or mixed 3.3V, 2.5V supply modes
- 0°C to 70°C ambient operating temperature
- Available in lead-free RoHS compliant package

BLOCK DIAGRAM

PIN ASSIGNMENT







TABLE 1. PIN DESCRIPTIONS

Number	Name	Т	уре	Description
1, 2, 12, 17, 25	GND	Power		Power supply ground.
3	LVCMOS_CLK	Input	Pulldown	Clock input. LVCMOS / LVTTL interface levels.
4	CLK_SEL	Input	Pulldown	Clock select input. Selects LVCMOS / LVTTL clock input when HIGH. Selects PCLK, nPCLK inputs when LOW. LVCMOS / LVTTL interface levels.
5	PCLK	Input	Pulldown	Non-inverting differential LVPECL clock input.
6	nPCLK	Input		Inverting differential LVPECL clock input. $V_{_{DD}}$ /2 default when left floating.
7	V _{DD}	Power		Power supply pin.
8, 16, 21, 29	V _{DDO}	Power		Output supply pins.
9, 10, 11, 13, 14, 15, 18, 19, 20, 22, 23, 24, 26, 27, 28, 30, 31, 32	Q17, Q16, Q15, Q14, Q13, Q12, Q11, Q10, Q9, Q8, Q7, Q6, Q5, Q4, Q3, Q2, Q1, Q0	Output		Clock outputs. LVCMOS / LVTTL interface levels.

NOTE: Pulldown refers to internal input resistors. See Table 2, Pin Characteristics, for typical values.

TABLE 2. PIN CHARACTERISTICS

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
C _{PD}	Power Dissipation Capacitance (per output)			6		pF
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ
R _{OUT}	Output Impedance		18		28	Ω

TABLE 3A. CLOCK SELECT FUNCTION TABLE

Control Input	Clock					
CLK_SEL	PCLK, nPCLK LVCMOS_CI					
0	Selected	De-selected				
1	De-selected	Selected				

TABLE 3B. CLOCK INPUT FUNCTION TABLE

	Ing	outs		Outputs	Input to Output Mode	Polarity
CLK_SEL	LVCMOS_CLK	PCLK	nPCLK	Q0:Q17	Input to Output Mode	Folarity
0	—	0	1	LOW	Differential to Single Ended	Non Inverting
0	—	1	0	HIGH	Differential to Single Ended	Non Inverting
0	_	0	Biased; NOTE 1	LOW	Single Ended to Single Ended	Non Inverting
0	_	1	Biased; NOTE 1	HIGH	Single Ended to Single Ended	Non Inverting
0	—	Biased; NOTE 1	0	HIGH	Single Ended to Single Ended	Inverting
0	—	Biased; NOTE 1	1	LOW	Single Ended to Single Ended	Inverting
1	0	—		LOW	Single Ended to Single Ended	Non Inverting
1	1	—		HIGH	Single Ended to Single Ended	Non Inverting

NOTE 1: Please refer to the Application Information section, "Wiring the Differential Input to Accept Single Ended Levels".

Absolute Maximum Ratings

Supply Voltage, V _{DD}	3.6V
Inputs, V _I	-0.3V to V_{DD} + 0.3V
Outputs, V _o	-0.3V to V_{DDO} + 0.3V
Input Current, I _{IN}	±20mA
Storage Temperature, T_{STG}	-40°C to 125°C

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Table 4A. DC Characteristics, $V_{\text{DD}} = V_{\text{DDO}} = 3.3V \pm 5\%$, Ta = 0° to 70°

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units	
V _{IH}	Input High Voltage LVCMOS_CLK			2.4		V _{DD}	V
V _{IL}	Input Low Voltage	LVCMOS_CLK				0.8	V
V _{PP}	Peak-to-Peak Input Voltage PCLK, nPCLK			500		1000	mV
V _{CMR}	Input Common Mode Voltage; NOTE 1, 2			V _{DD} - 1.4		V _{DD} - 0.6	V
I _{IN}	Input Current					±200	μA
V _{OH}	Output High Voltage		I _{он} = -20mA	2.4			V
V _{OL}	Output Low Voltage	I _{oL} = 20mA			0.5	V	
I _{DD}	Power Supply Current					25	mA

NOTE 1: For single ended applications, the maximum input voltage for PCLK, nPCLK is V_{DD} + 0.3V.

NOTE 2: Common mode voltage is defined as $\rm V_{{}_{IH}}$

TABLE 4B. DC Characteristics, $V_{\text{DD}} = 3.3V \pm 5\%$, $V_{\text{DDO}} = 2.5V \pm 5\%$, Ta = 0° to 70°

Symbol	Parameter	Parameter			Typical	Maximum	Units
V _{IH}	Input High Voltage LVCMOS_CLK			2.4		V _{DD}	V
V _{IL}	Input Low Voltage	LVCMOS_CLK				0.8	V
V _{PP}	Peak-to-Peak Input Voltage PCLK, nPCLK			300		1000	mV
V _{CMR}	Input Common Mode Voltage; NOTE 1, 2			V _{DD} - 1.4		V _{DD} - 0.6	V
I _{IN}	Input Current					±200	μA
V _{OH}	Output High Voltage		I _{он} = -20mA	1.8			V
V _{OL}	Output Low Voltage		$I_{OL} = 20 \text{mA}$			0.5	V
I _{DD}	Power Supply Current					25	mA

NOTE 1: For single ended applications, the maximum input voltage for PCLK, nPCLK is V $_{\rm DD}$ + 0.3V. NOTE 2: Common mode voltage is defined as V $_{\rm IH}$.

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V _{IH}	Input High Voltage	LVCMOS_CLK		2		V _{DD}	V
V	Input Low Voltage	LVCMOS_CLK				0.8	V
V _{PP}	Peak-to-Peak Input Voltage	PCLK, nPCLK		300		1000	mV
V _{CMR}	Input Common Mode Voltage; NOTE 1, 2	PCLK, nPCLK		V _{DD} - 1.4		V _{DD} - 0.6	V
I _{IN}	Input Current					±200	μA
V _{OH}	Output High Voltage		I _{он} = -12mA	1.8			V
V _{OL}	Output Low Voltage		I _{oL} = 12mA			0.5	V
I _{DD}	Power Supply Current					25	mA

TABLE 4C. DC CHARACTERISTICS,	$V_{DD} = V_{DDO} = 2.5V \pm 5\%$, Ta = 0° to 70°
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NOTE 1: For single ended applications, the maximum input voltage for PCLK, nPCLK is V_{DD} + 0.3V.

NOTE 2: Common mode voltage is defined as V_{III} .

TABLE 5A. AC CHARACTERISTICS, $V_{\text{DD}} = V_{\text{DDO}} = 3.3V \pm 5\%$, TA = 0° to 70°

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
f _{MAX}	Output Frequency					250	MHz
+	Propagation Delay	PCLK, nPCLK; NOTE 1, 5	f 150MHz	1.6		3.0	ns
t _{pLH}	Fropagation Delay	LVCMOS_CLK; NOTE 2, 5	f 150MHz	1.8		3.0	ns
÷	Propagation Dalay	PCLK, nPCLK; NOTE 1, 5	f > 150MHz	1.6		3.3	ns
t _{pLH}	Propagation Delay	LVCMOS_CLK; NOTE 2, 5	f > 150MHz	1.8		3.2	ns
tak(a)	Output Skew; NOTE 3, 5	PCLK, nPCLK	Measured on rising edge @V _{DDO} /2			85	ps
tsk(o)		LVCMOS_CLK				85	ps
tol(mm)	Part-to-Part Skew;	PCLK, nPCLK	f 150MHz			1.4	ns
tsk(pp)	NOTE 6	LVCMOS_CLK	f 150MHz			1.2	ns
t = l = (= = =)	Part-to-Part Skew;	PCLK, nPCLK	f > 150MHz			1.7	ns
tsk(pp)	NOTE 6	LVCMOS_CLK	f > 150MHz			1.4	ns
t = 1 - ()	Part-to-Part Skew;	PCLK, nPCLK	Measured on			850	ps
tsk(pp)	NOTE 4, 5	LVCMOS_CLK	rising edge @V _{DDO} /2			750	ps
t _R , t _F	Output Rise/Fall Time		20% to 80%	400		800	ps
			f 150MHz	45		55	%
odc	Output Duty Cycle		150MHz < f 250MHz	40		60	%

All parameters measured at 200MHz unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the output $V_{\text{DDO}}/2$.

NOTE 2: Measured from $V_{_{\rm DD}}/2$ to $V_{_{\rm DDO}}/2$.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at $V_{DDO}/2$.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltages, same temperature,

and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at $V_{_{\rm DDO}}/2$.

NOTE 5: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 6: Defined as skew between outputs on different devices, across temperature and voltage ranges, and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at $V_{_{DDO}}/2$.

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
f _{MAX}	Output Frequency					250	MHz
+	Propagation Delay	PCLK, nPCLK; NOTE 1, 5	f 150MHz	1.7		3.2	ns
t _{pLH}	FTOPagation Delay	LVCMOS_CLK; NOTE 2, 5	f 150MHz	1.7		3.0	ns
+	Bropagation Dolov	PCLK, nPCLK; NOTE 1, 5	f > 150MHz	1.6		3.4	ns
t _{pLH}	Propagation Delay	LVCMOS_CLK; NOTE 2, 5	f > 150MHz	1.8		3.3	ns
tok(o)	Output Skew; NOTE 3, 5	PCLK, nPCLK	Measured on			150	ps
tsk(o)		LVCMOS_CLK	rising edge $@V_{DDO}/2$			150	ps
tok(nn)	Part-to-Part Skew;	PCLK, nPCLK	f 150MHz			1.5	ns
tsk(pp)	NOTE 6	LVCMOS_CLK	f 150MHz			1.3	ns
t = 1 - ()	Part-to-Part Skew;	PCLK, nPCLK	f > 150MHz			1.8	ns
tsk(pp)	NOTE 6	LVCMOS_CLK	f > 150MHz			1.5	ns
tal (mm)	Part-to-Part Skew;	PCLK, nPCLK	Measured on			850	ps
tsk(pp)	NOTE 4, 5	LVCMOS_CLK	rising edge @V _{DDO} /2			750	ps
t _R , t _F	Output Rise/Fall Time		20% to 80%	400		800	ps
odc			f < 134MHz	45		55	%
ouc	Output Duty Cycle		134MHz f < 250MHz	40		60	%

TABLE 5B. AC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$, TA = 0° TO 70°

All parameters measured at 200MHz unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the output $V_{DDO}/2$.

NOTE 2: Measured from $V_{DD}/2$ to $V_{DDO}/2$.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at $V_{DDO}/2$. NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltages, same temperature, and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at $V_{DDO}/2$.

NOTE 5: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 6: Defined as skew between outputs on different devices, across temperature and voltage ranges, and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at $V_{\text{DDO}}/2$.

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
f _{MAX}	Output Frequency					200	MHz
+	Propagation Delay;	PCLK, nPCLK; NOTE 1, 5	f 150MHz	1.2		3.8	ns
t _{pLH}	Fropagation Delay,	LVCMOS_CLK; NOTE 2, 5	f 150MHz	1.5		3.2	ns
+	Propagation Dolour	PCLK, nPCLK; NOTE 1, 5	f > 150MHz	1.5		3.7	ns
t _{pLH}	Propagation Delay;	LVCMOS_CLK; NOTE 2, 5	f > 150MHz	2		3.6	ns
tak(a)	Output Skew; NOTE 3, 5	PCLK, nPCLK	Measured on			150	ps
tsk(o)		LVCMOS_CLK	rising edge $@V_{DDO}/2$			150	ps
tak(nn)	Part-to-Part Skew;	PCLK, nPCLK	f 150MHz			2.6	ns
tsk(pp)	NOTE 6	LVCMOS_CLK	f 150MHz			1.7	ns
tal(mm)	Part-to-Part Skew;	PCLK, nPCLK	f > 150MHz			2.2	ns
tsk(pp)	NOTE 6	LVCMOS_CLK	f > 150MHz			1.7	ns
tal(mm)	Part-to-Part Skew;	PCLK, nPCLK	Measured on			1.2	ns
tsk(pp)	NOTE 4, 5	LVCMOS_CLK	rising edge @V _{DDO} /2			1.0	ns
t _R , t _F	Output Rise/Fall Time		20% to 80%	400		800	ps
			f < 134MHz	45		55	%
odc	Output Duty Cycle		134MHz f 200MHz	40		60	%

Table 5C. AC Characteristics, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, Ta = 0° to 70°

All parameters measured at 200MHz unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the output $V_{_{DDO}}/2$.

NOTE 2: Measured from $V_{_{\rm DD}}\!/2$ to $V_{_{\rm DDO}}\!/2.$

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at $V_{_{DDO}}/2$. NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltages, same temperature, and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at $V_{_{DDO}}/2$.

NOTE 5: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 6: Defined as skew between outputs on different devices, across temperature and voltage ranges,

and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at $V_{DDO}/2$.



PARAMETER MEASUREMENT INFORMATION





PROPAGATION DELAY

APPLICATION INFORMATION

WIRING THE DIFFERENTIAL INPUT TO ACCEPT SINGLE ENDED LEVELS

Figure 1 shows how the differential input can be wired to accept single ended levels. The reference voltage V_REF = $V_{DD}/2$ is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of R1 and R2 might need to be adjusted to position the V_REF

in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and V_{DD} = 3.3V, V_REF should be 1.25V and R2/R1 = 0.609.



RECOMMENDATIONS FOR UNUSED INPUT AND OUTPUT PINS

INPUTS:

CLK INPUT:

For applications not requiring the use of a clock input, it can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from the CLK input to ground.

PCLK/nPCLK INPUT:

For applications not requiring the use of a differential input, both the PCLK and nPCLK pins can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from PCLK to ground.

LVCMOS CONTROL PINS:

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A $1k\Omega$ resistor can be used.

OUTPUTS:

LVCMOS OUTPUT:

All unused LVCMOS output can be left floating. We recommend that there is no trace attached.

LVPECL CLOCK INPUT INTERFACE

The PCLK /nPCLK accepts LVPECL, CML, SSTL and other differential signals. Both V_{SWING} and V_{OH} must meet the V_{PP} and V_{CMR} input requirements. *Figures 2A to 2E* show interface examples for the PCLK/nPCLK input driven by the most common driver types. The input interfaces



FIGURE 2A. PCLK/nPCLK INPUT DRIVEN BY AN OPEN COLLECTOR CML DRIVER



FIGURE 2C. PCLK/nPCLK INPUT DRIVEN BY A 3.3V LVPECL DRIVER



FIGURE 2E. PCLK/nPCLK INPUT DRIVEN BY AN SSTL DRIVER

suggested here are examples only. If the driver is from another vendor, use their termination recommendation. Please consult with the vendor of the driver component to confirm the driver termination requirements.



FIGURE 2B. PCLK/nPCLK INPUT DRIVEN BY A BUILT-IN PULLUP CML DRIVER



FIGURE 2D. PCLK/nPCLK INPUT DRIVEN BY A 3.3V LVPECL DRIVER WITH AC COUPLE



FIGURE 2F. PCLK/nPCLK INPUT DRIVEN BY A 3.3V LVDS DRIVER

RELIABILITY INFORMATION

Table 6. $\boldsymbol{\theta}_{JA} \text{vs.}$ Air Flow Table for 32 Lead LQFP

	-		
	0	200	500
Single-Layer PCB, JEDEC Standard Test Boards	67.8°C/W	55.9°C/W	50.1°C/W
Multi-Layer PCB, JEDEC Standard Test Boards	47.9°C/W	42.1°C/W	39.4°C/W

TRANSISTOR COUNT

The transistor count for ICS83940-01 is: 819

PACKAGE OUTLINE - Y SUFFIX FOR 32 LEAD LQFP



TABLE 7. PACKAGE DIMENSIONS

JEDEC VARIATION ALL DIMENSIONS IN MILLIMETERS				
SYMBOL	BBA			
STMBOL	MINIMUM	NOMINAL	MAXIMUM	
N	32			
Α			1.60	
A1	0.05		0.15	
A2	1.35	1.40	1.45	
b	0.30	0.37	0.45	
с	0.09		0.20	
D	9.00 BASIC			
D1	7.00 BASIC			
D2	5.60 Ref.			
E	9.00 BASIC			
E1	7.00 BASIC			
E2	5.60 Ref.			
е	0.80 BASIC			
L	0.45 0.60 0.75			
θ	0°		7 °	
ccc	0.10			

Reference Document: JEDEC Publication 95, MS-026

TABLE 8. ORDERING INFORMATION

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
83940DY-01LF	ICS83940D01L	32 Lead "Lead-Free" LQFP	tray	0°C to 70°C
83940DY-01LFT	ICS83940D01L	32 Lead "Lead-Free" LQFP	reel	0°C to 70°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS complaint.

REVISION HISTORY SHEET					
Rev	Table	Page	Description of Change	Date	
A	Τ8	1 9 10 13	Added Lead-Free bullet. Added <i>Recommendations for Unused Input and Output Pins.</i> Updated <i>LVPECL Clock Input Interface</i> section. Added Lead-Free part number, marking and note.	11/18/05	
А	Т8	13 15	Updated datasheet's header/footer with IDT from ICS. Removed ICS prefix from Part/Order Number column. Added Contact Page.	8/4/10	
A	Т	13	Removed Leaded devices Updated Datasheet format	11/4/14	



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